Power MOSFET

30 V, 64 A, Single N-Channel, SO-8FL

Features

- Low R_{DS(ON)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Low RG
- These are Pb-Free Devices*

Applications

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Vo	Drain-to-Source Voltage		V_{DSS}	30	V
Gate-to-Source Vol	tage		V_{GS}	±20	V
Continuous Drain Current R _{θJA} (Note 1)		T _A = 25°C T _A = 85°C	I _D	15 11	A
Power Dissipation R _{θJA} (Note 1)		T _A = 25°C T _A = 85°C	P_{D}	2.17 1.13	W
Continuous Drain Current R _{θJA} – t≤10 sec		T _A = 25°C T _A = 85°C	I _D	24 17	Α
Power Dissipation $R_{\theta JA} t \le 10 \text{ sec}$	Steady	T _A = 25°C T _A = 85°C	P _D	5.7 2.9	W
Continuous Drain Current R _{θJA} (Note 2)	State	T _A = 25°C T _A = 85°C	I _D	9.5 7.0	Α
Power Dissipation R _{θJA} (Note 2)		T _A = 25°C T _A = 85°C	P _D	0.87 0.45	W
Continuous Drain Current R _{θJC} (Note 1)		T _C = 25°C T _C = 85°C	I _D	64 46	Α
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C T _C = 25°C	P _D	42.4 22	W
Pulsed Drain Current		T _A = 25°C, t _p = 10 μs		192	Α
Operating Junction a Temperature	Operating Junction and Storage Temperature		T _J , T _{STG}	–55 to +150	°C
Source Current (Body Diode)		I _S	35	Α	
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain-to-Source Avalanche Energy (T_J = 25°C, V_{DD} = 24 V, V_{GS} = 10 V, I_L = 27 A, L = 0.3 mH, R_G = 25 Ω)		EAS	109	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

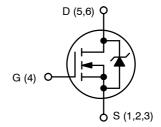
1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.



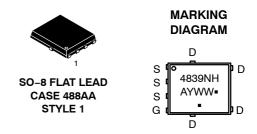
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
2014	5.5 m Ω @ 10 V	
30 V	10.3 m Ω @ 4.5 V	64 A



N-CHANNEL MOSFET



A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4839NHT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4839NHT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Surface-mounted on FR4 board using the minimum recommended pad size.
 *For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.95	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	57.6	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	143.3	C/VV
Junction-to-Ambient (t≤10 sec)	$R_{ heta JA}$	22	

ELECTRICAL CHARACTERISTICS (T _J =	= 25°C unless o	otherwise specified)					
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				27.5		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	μΑ
		V _{DS} = 24 V	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.5		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to 11.5 V	I _D = 30 A		4.3	5.5	
			I _D = 15 A		4.3		
		V _{GS} = 4.5 V	I _D = 30 A		8.2	10.3	mΩ
			I _D = 15 A		7.8		1
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 50 A			60		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						
Input Capacitance	C _{ISS}				1744	2354	
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			355	479	pF
Reverse Transfer Capacitance	C _{RSS}				191	296	
Total Gate Charge	Q _{G(TOT)}				12.9	19.5	
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			2.2	3.3	nC
Gate-to-Source Charge	Q_{GS}				5.2	7.8	
Gate-to-Drain Charge	Q_{GD}				5.4	8.0	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			31	43.5	nC
SWITCHING CHARACTERISTICS (Note 6)					•		-
Turn-On Delay Time	t _{d(ON)}				13.4	20	
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			22.5	33.7	ns
Turn-Off Delay Time	t _{d(OFF)}				16	24	
Fall Time	t _f				5.3	7.9	
	-					-	

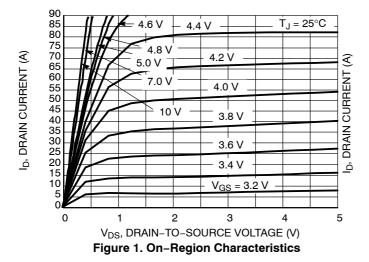
Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 6)						
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			8.1	12.2	- ns
Rise Time	t _r				19.6	29.4	
Turn-Off Delay Time	t _{d(OFF)}				23.2	34.9	
Fall Time	t _f				3.4	5.1	
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V, I _S = 30 A	T _J = 25°C		0.83	1.2	· v
			T _J = 125°C		0.73		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 30 A			19.3		ns
Charge Time	t _a				10.1		
Discharge Time	t _b				9.2		
Reverse Recovery Charge	Q _{RR}				6.3		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	T _A = 25°C			0.93		nH
Drain Inductance	L _D				0.005		nH
Gate Inductance	L _G				1.84		nH
Gate Resistance	R_{G}				0.9		Ω

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.



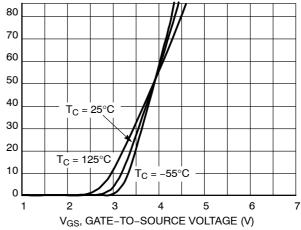
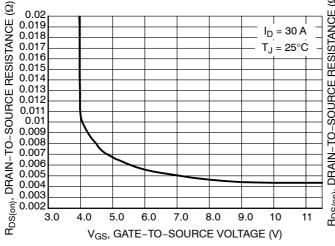


Figure 2. Transfer Characteristics



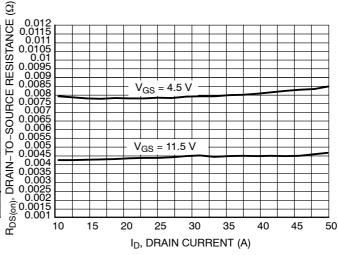
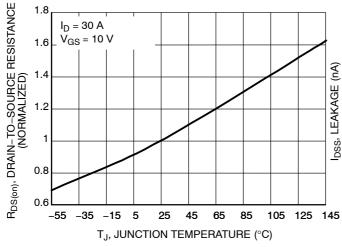


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Gate Voltage



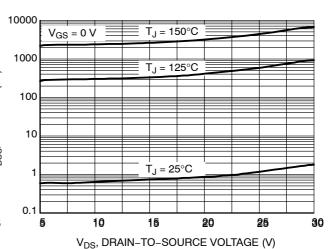


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage

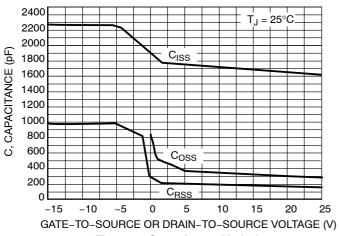


Figure 7. Capacitance Variation

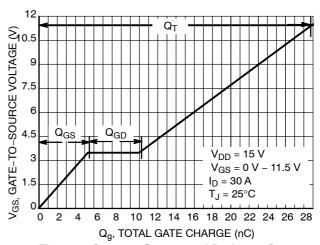


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

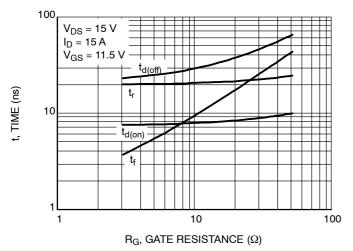


Figure 9. Resistive Switching Time Variation versus Gate Resistance

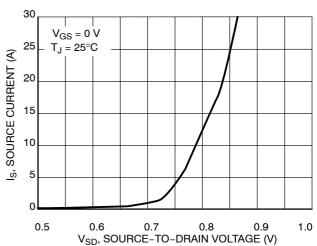


Figure 10. Diode Forward Voltage versus Current

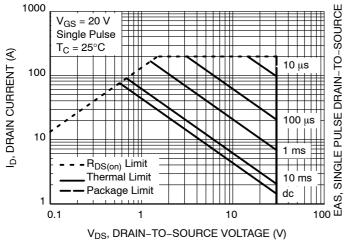


Figure 11. Maximum Rated Forward Biased Safe Operating Area

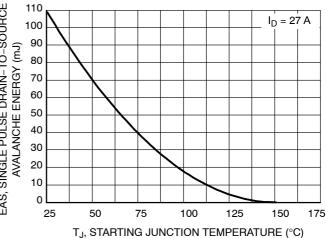


Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

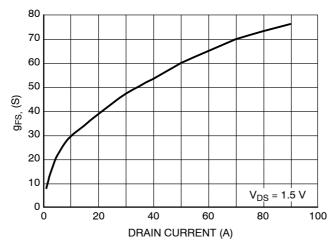
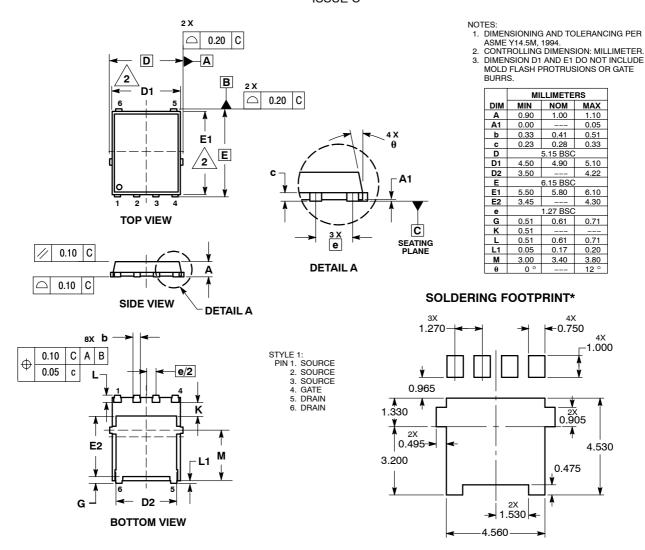


Figure 13. G_{FS} versus Drain Current

PACKAGE DIMENSIONS

DFN6 5x6, 1.27P (SO8 FL)CASE 488AA-01 ISSUE C



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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